



西北工业大学
NORTHWESTERN POLYTECHNICAL UNIVERSITY



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SENSROC12: A high-count-rate low-noise front-end readout ASIC for Si-PIN-based personal dosimeter

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Outline

1. Introduction

- Personal dosimeter
- Si-PIN detector
- ASIC requirements

2. Readout techniques for Si-PIN detectors

- State-of-the-art of Si-PIN readout circuits
- Noise models and noise optimization
- Proposed readout circuits

3. Experimental results and Discussions

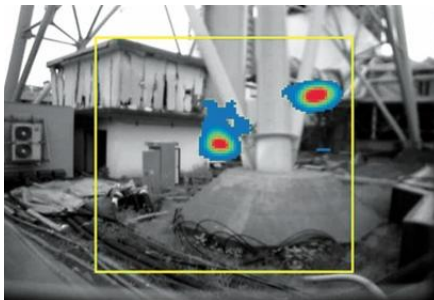
- Experimental results
- Performance overview

4. Conclusions and perspectives

Introduction

◆ Personal Dosimeter

- Ionization radiation of nuclear imaging in hospital and research in laboratories
- military personal searching for nuclear materials
- Occupational exposure in nuclear power plants



1. Main requirements

- Energy spectrum($\pm 30\%$, ^{137}Cs)
- Relative intrinsic error($\pm 15\%$, ^{137}Cs)
- Angular response($\pm 20\%$, ^{137}Cs)
- Energy range(48keV $\sim$ 7MeV)
- Dose(1 μSv $\sim$ 1Sv)/Dose rate range(1 $\mu\text{Sv/h}$ $\sim$ 1Sv/h)
- Temperature (-40-85 $^{\circ}\text{C}$)
- Low power dissipation

2. Other

- Waterproof, dropping and shock prevention
- electromagnetic radiation hardness
- Electrostatic protection

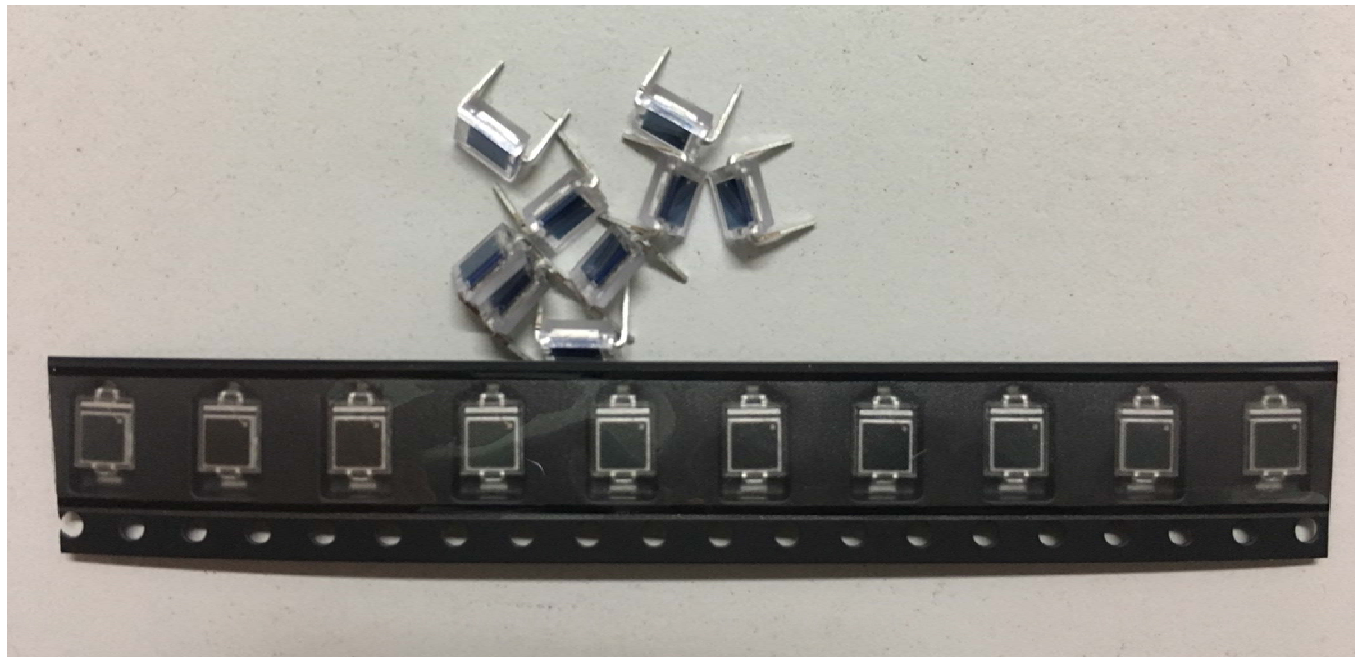
Introduction

■ Radiation Detectors

	PMT	APD	Silicon Photodiode	CZT,CdTe
Size	Bulky	Compat, thin	Compat, thin	Compat, thin
Gain	$10^6 \sim 10^7$	$10^2 \sim 10^3$	$10^2 \sim 10^3$	$10^2 \sim 10^3$
Noise	Low	moderate	Low	Low
Threshold Sensitivity	1 ph.e	10 ph.e	1 ph.e	--
Timing Resolution	~ 0.5 ns	~ 1 ns	~ 0.5 ns	~ 7 ns
Energy Resolution	~ 10 %	~ 13 %	~ 10 %	~ 4 % (0.2 ~ 20 keV)
Bias Voltage	800 ~ 1500 V	100 ~ 2000V	25 ~ 50 V	800 ~ 1500 V
Cost	\$	\$\$	\$\$\$(\$)	\$\$\$

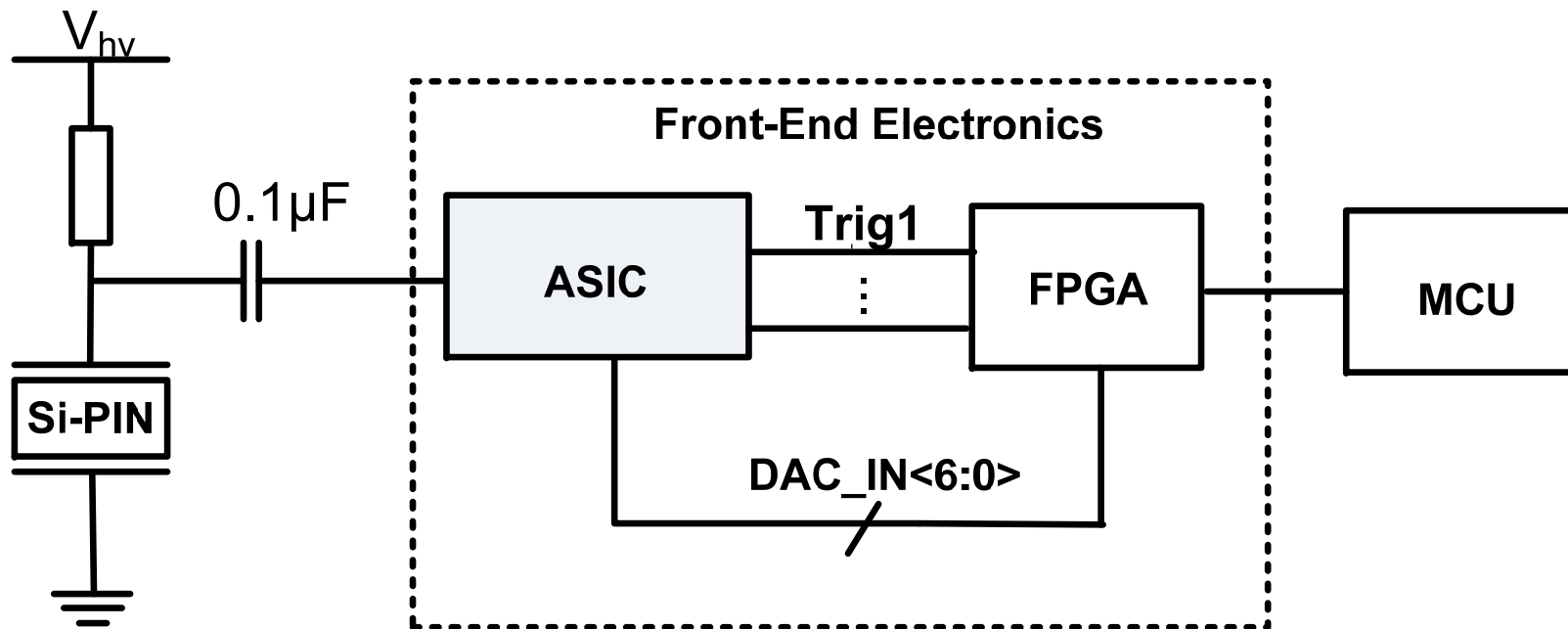
Introduction

- **Proposed detector → Si-PIN detector**
 - ❑ Each dimension: 5.4 mm × 4.3 mm × 3.2 mm;
 - ❑ Radiant sensitive area: 7.5 mm²
 - ❑ Detector capacitance: ~20 pF
 - ❑ High radiant sensitivity
 - ❑ Fast response times



Introduction

- Proposed front-end electronics



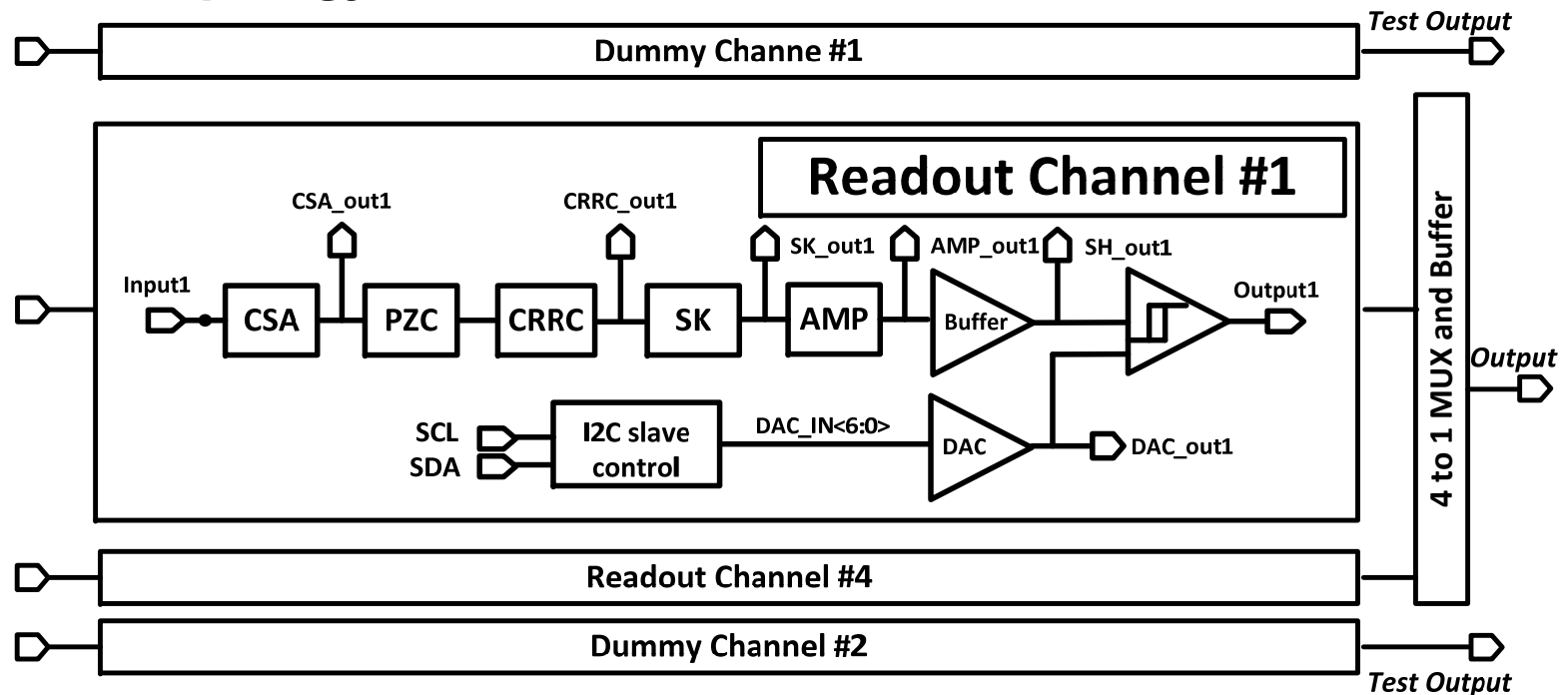
Introduction

■ ASIC requirement

Power Voltage	+/- 1.65V
Bias Voltage	5 V
Detector Capacitance	20 pF
Input Charge Range	0.2 fC ~ 15 fC
Shaping Time	<1 μ s
Gain	> 60 mW/fC
ENC	<100 e ⁻ @0 pF
Counting Rate	1 MCPS
Static Power Dissipation	1 mW/channel (not include DAC and discrimination) 1.2 mW/channel (include DAC and discrimination)

Readout techniques for Si-PIN detectors

■ Proposed topology

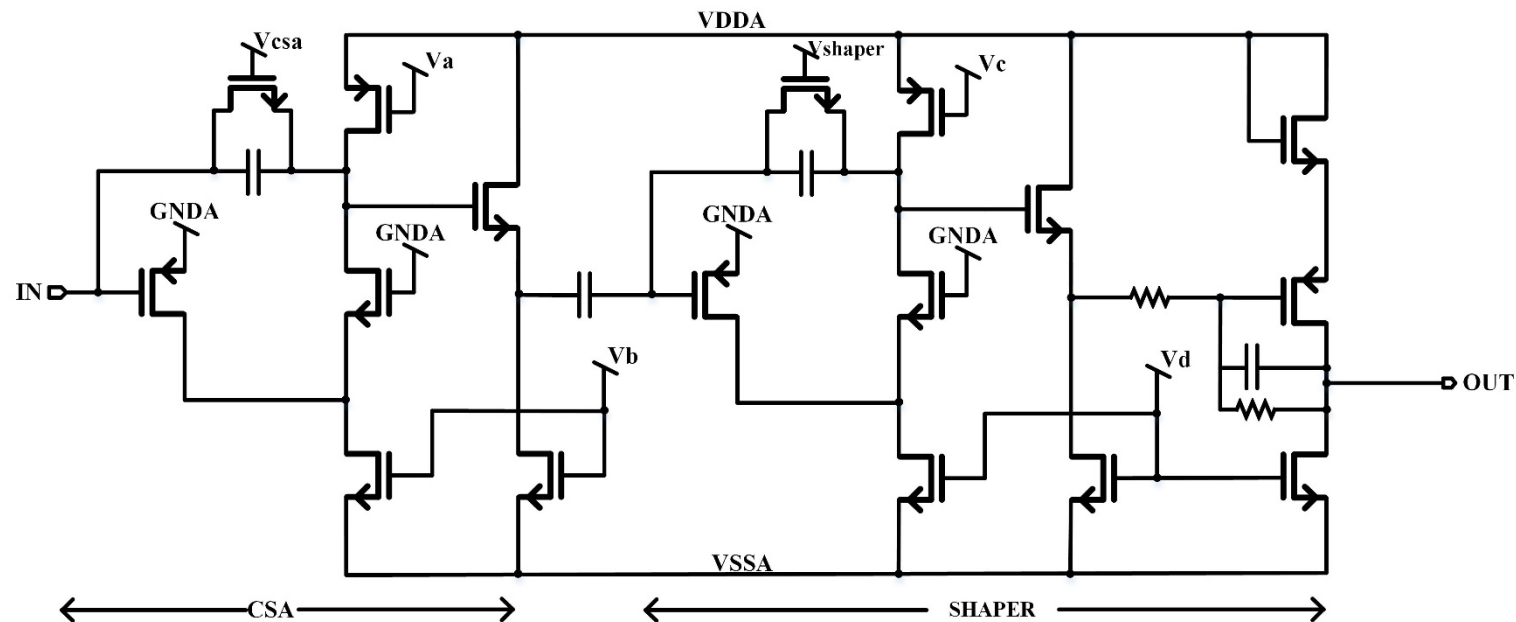


■ Main features

- ❑ **Preamplifier: charge sensitive amplifier + PZC**
- ❑ **Pulse shaper: CR-RC + SK + AMP(positive output)**
- ❑ **Discriminator: high speed comparator + DAC(threshold adjustment)**

Readout techniques for Si-PIN detectors

■ Proposed schematic of readout circuit



■ Main Features

- **Input stage: PMOS + cascode**

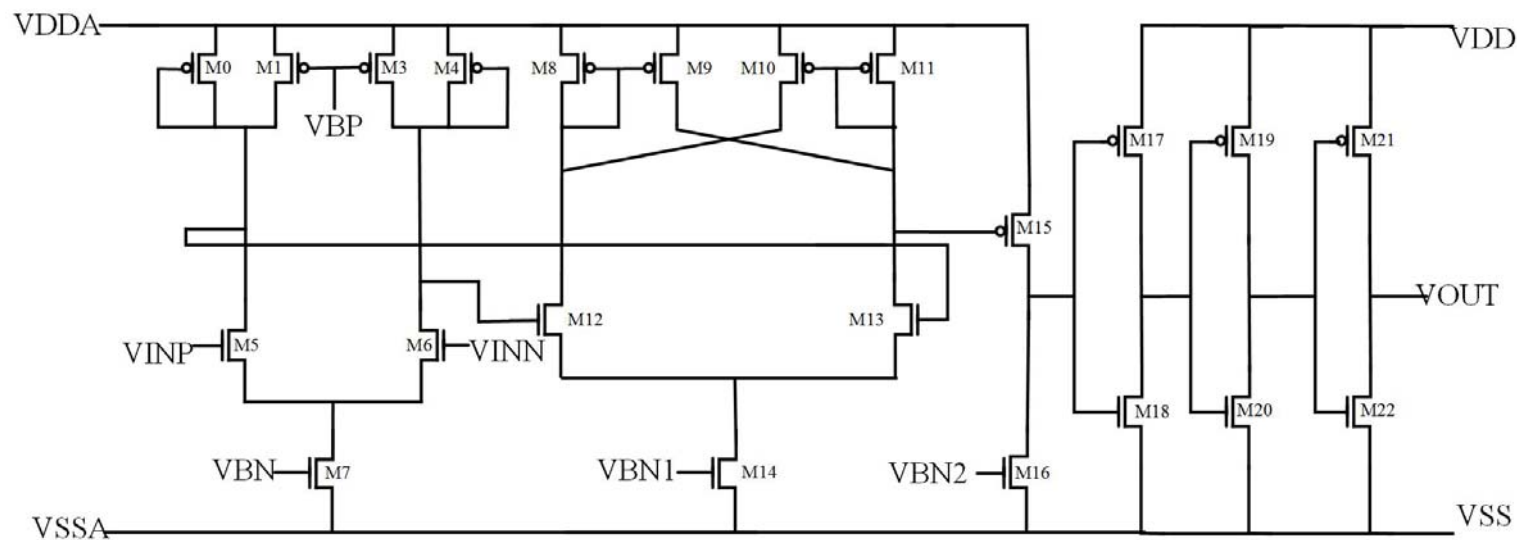
$$H(s) = -\frac{V_{OUT}(s)}{i_D(s)} \approx -\frac{1}{sC_F + \frac{1}{R_F}}$$

- **Pulse shaper: cascode CR-RC + simplified SK**

$$H(s) = -\frac{sR_2C_1}{(1 + sR_1C_1)(1 + sR_2C_2)}$$

Readout techniques for Si-PIN detectors

■ Proposed hysteresis discrimination



■ Main Features

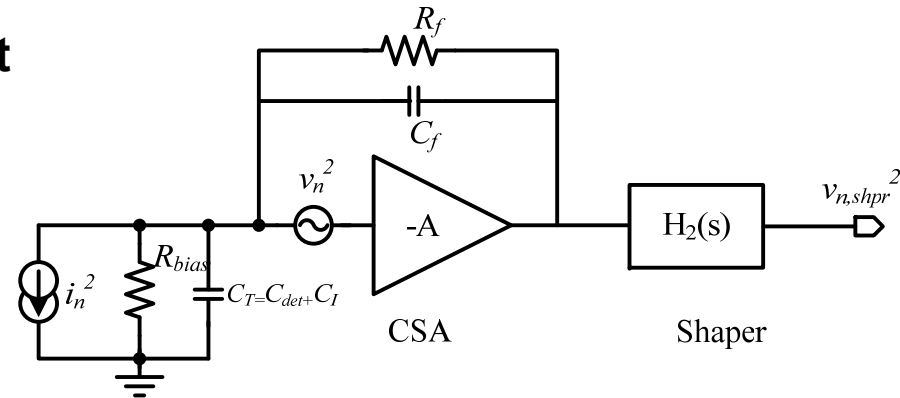
- **Hysteresis voltage → 5mv**
- **Three stage cascode structure**
- **Isolate analog/digital power supplies**

Readout techniques for Si-PIN detectors

- The power spectral density of current noise and voltage noise at the input of CSA

$$\overline{i_n^2} = 2qI_{\text{det}} + \frac{4kT}{R_{\text{bias}}} + \frac{4kT}{R_f}$$

$$\overline{v_n^2} = 4kT \frac{\gamma_n}{g_{m1}} + \frac{K_f}{C_{\text{ox}}^2} \frac{1}{WL}$$



- The output noise of shaper

$$\overline{v_{n,shpr}^2} = \frac{1}{C_F^2} \left[\frac{t_p}{8} \left(2qI_{\text{det}} + \frac{4kT}{R_{\text{bias}}} + \frac{4kT}{R_f} \right) + (C_F + C_T)^2 \left(\frac{4kT\gamma_n}{8t_p g_{m1}} + \frac{K_f}{2C_{\text{ox}}^2} \frac{1}{WL} \right) \right]$$

- The equivalent noise charge is

$$ENC = \frac{\sqrt{\overline{v_{n,shpr}^2}}}{v_{shpr,max} (Q_{in} = 1 \text{ electron})}$$

Readout techniques for Si-PIN detectors

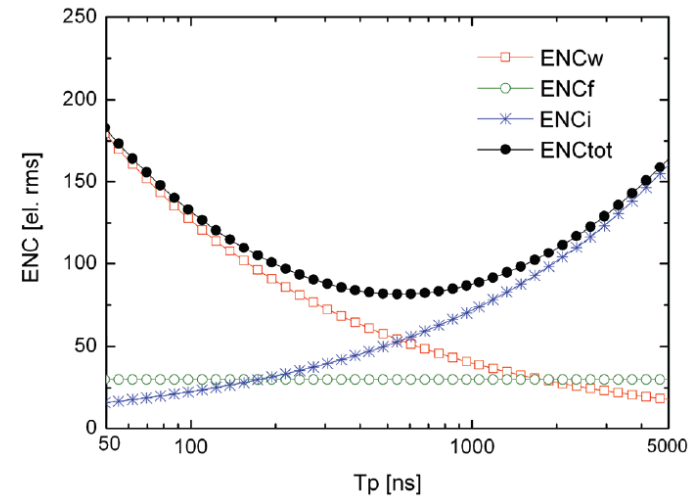
- The **ENC** can be calculated as

$$ENC = e \sqrt{\frac{t_p}{8} \left(2qI_{\text{det}} + \frac{4kT}{R_{\text{bias}}} + \frac{4kT}{R_f} \right) + (C_F + C_T)^2 \left(\frac{4kT\gamma_n}{8t_p g_{m1}} + \frac{K_f}{2C_{\text{ox}}^2} \frac{1}{WL} \right)}$$

- The ENC can be divided into three parts according to **the current noise source, the voltage noise source and the 1/f noise source.**

$$ENC^2 = ENC_i^2 + ENC_v^2 + ENC_f^2$$

$$\left\{ \begin{array}{l} ENC_i^2 = 0.462t_p \left[qI_{\text{det}} + 2kT \left(\frac{1}{R_{\text{bias}}} + \frac{1}{R_f} \right) \right] \\ ENC_v^2 = 3.696 \frac{(C_F + C_T)^2}{t_p} \frac{kT\gamma_n}{g_{m1}} \\ ENC_f^2 = 3.696(C_F + C_T)^2 \frac{K_f}{C_{\text{ox}}^2} \frac{1}{WL} \end{array} \right.$$



** P. Grybos. "Front-end Electronics for Multichannel Semiconductor Detector Systems", Warsaw, 2010

Readout techniques for Si-PIN detectors

- The minimum ENC_v is obtained if

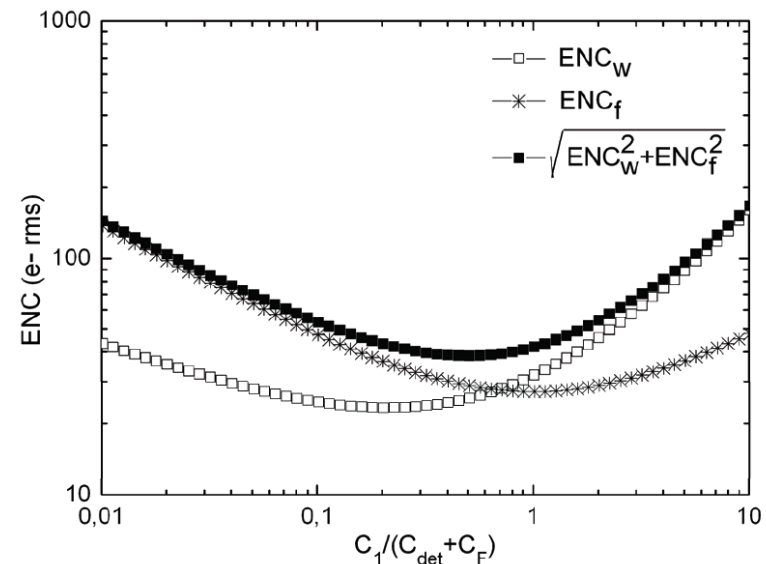
$$C_I = \frac{C_{\text{det}} + C_F}{3} \qquad W_{1,opt} = \frac{C_{\text{det}} + C_F}{2C_{ox}L_{\text{min}} + 6C_{ov}}$$

- The minimum of ENC_f is obtained if

$$C_I = C_{\text{det}} + C_F$$

The optimum C_I is closer to $(C_{\text{det}} + C_F)/3$ for short peaking time.

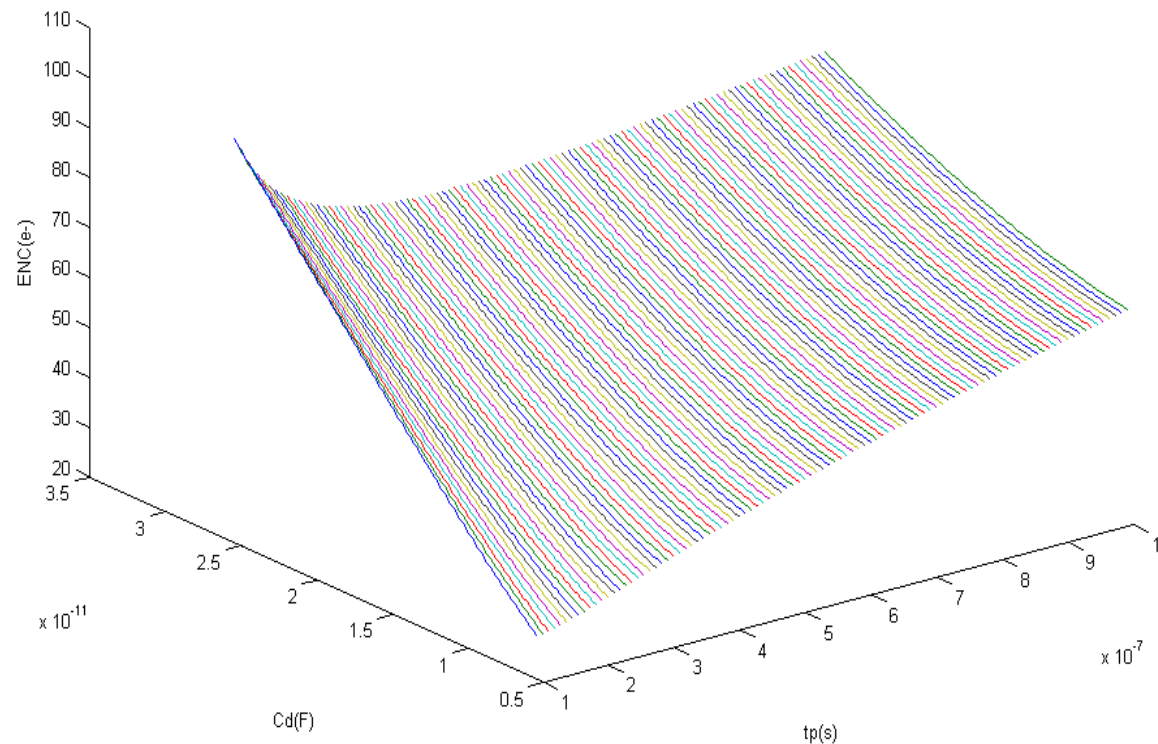
When the peaking time is longer, $(C_{\text{det}} + C_F)$ is more appropriate.



** P. Grybos. "Front-end Electronics for Multichannel Semiconductor Detector Systems", Warsaw, 2010

Readout techniques for Si-PIN detectors

■ Noise analysis



$C_f = 50 \text{ fF}$

$C_d = 20 \text{ pF}$

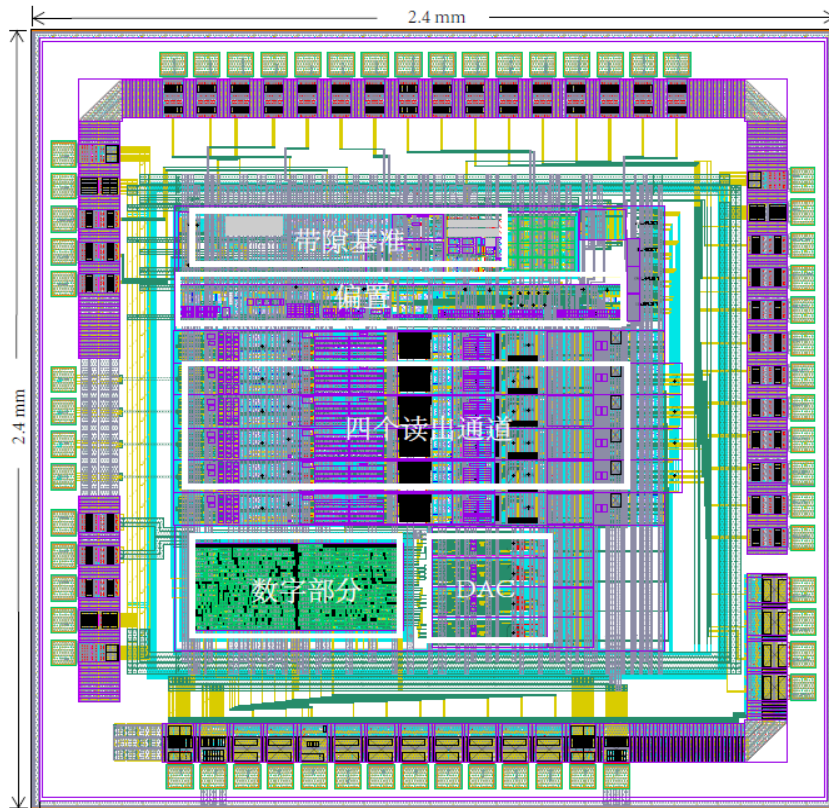
$W = 3000 \text{ } \mu\text{m}$

$L = 400 \text{ nm}$

$I_D = 400 \text{ } \mu\text{A}$

$T_p = 250 \text{ ns}$

Experimental results and Discussions



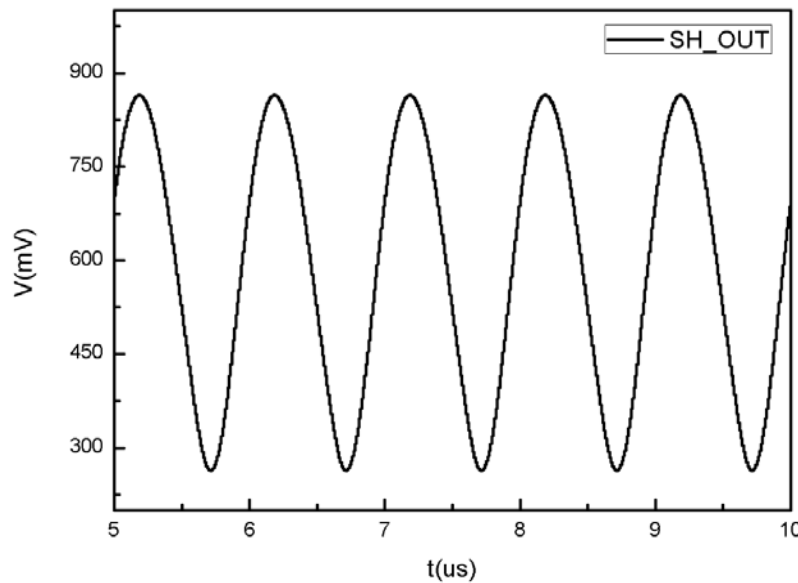
ASIC Layout

Process	CMOS 0.35 μ m 3.3V
Channel numbers	4
Die size (mm²)	2.4 $\times$ 2.4
Power Diss.	1 mW/Ch.
Dynamic Range	0.2 fC $\sim$ 16 fC
Non-linearity	< 3%
Gain	65 mV/fC
ENC	85 e @ 0 pF
Count Rate	1 MCPS
Peak Time	$\sim$ 0.5 μ s
Applications	Personal dosimeter and Portable spectrometer

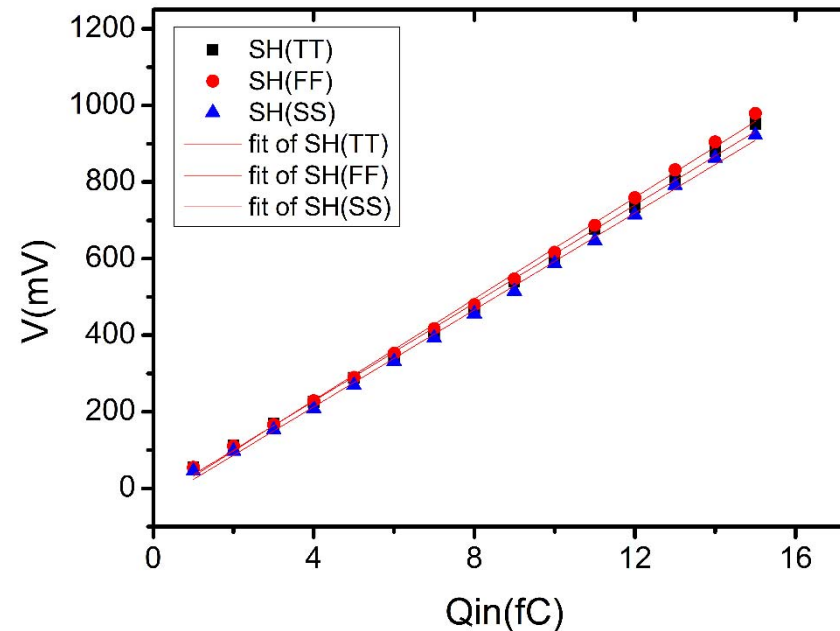
ASIC Overall Performance

Experimental results and Discussions

- The maximum count rate is about 1MCPS.
- Input range $\rightarrow 0 \sim 16$ fC; gain $\rightarrow 65$ mV/fC (Typical)



Output waveform

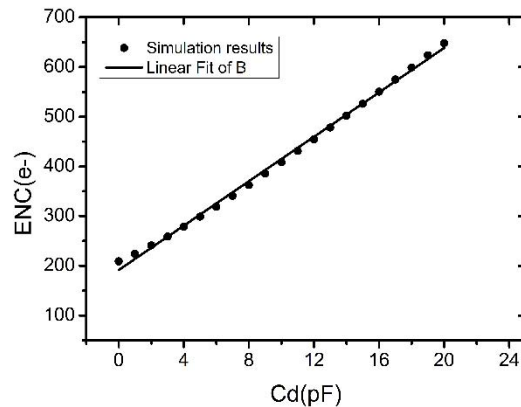


SH_out voltage VS. Q_{in}

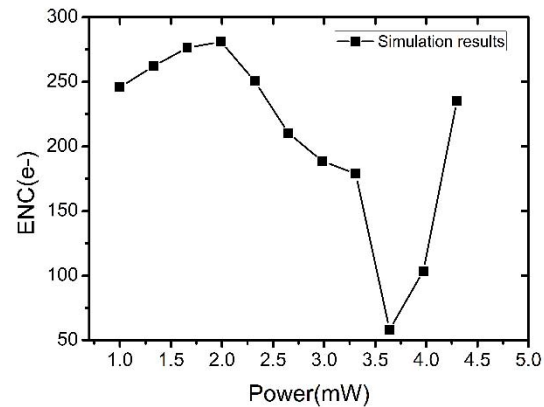
Experimental results and Discussions

■ Noise performance

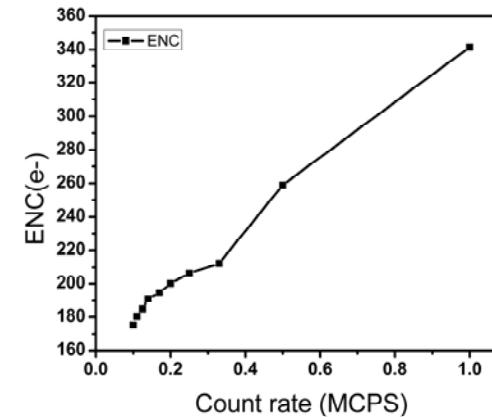
□ $ENC = 209 \text{ e}^- + 20 \text{ e}^- / \text{pF} (@ 1 \text{ MCPS})$



ENC vs. C_d



ENC vs. Power dissipation



ENC vs. Count rate

Experimental results and Discussions

Parameters	IDeF-X, 2009	2DASIC, 2009	STS-XYTER, 2013	IDE4184, 2015	This work
Process	CMOS 0.35 μ m	CMOS 0.35 μ m	CMOS 0.18 μ m	CMOS 0.35 μ m	CMOS 0.35 μ m
Channel numbers	32	16	128	128	4
Die size (mm ²)	2.8 $\times$ 6.4	2.95 $\times$ 2.95	10 $\times$ 6.5	8.04 $\times$ 7.37	2.4 $\times$ 2.4
Power Diss.	3mW / Ch.	0.15 mW / Ch.	3.1 mW / Ch.	90mW/ 128 Ch	1 mW/Ch.
Dynamic Range	0~8 fC	-12 fC ~+9 fC	-12 fC ~+9 fC	-25 fC	0.2 fC ~ 15 fC
ENC	33e+7 e/pF	88 e@ 0 pF	321 e@ 0 pF	130 e@ 0 pF	209 e + 20 e/pF
Count Rate	50 KCPS	30 KCPS	150 KCPS	92 KCPS	1 MCPS
FOM(ENC*Pow er Diss / Count Rate)	1.98	0.44	6.6	0.99	0.209

Conclusions and Perspectives

Conclusions for this presentation

- Proposed a novel front-end ASIC for Si-PIN-based personal dosimeter.
- An four-channel front-end readout prototype chip in 0.35 μm CMOS process.
- The simulation results show that the proposed ASIC can be employed for Si-PIN detector applications.
- Main experimental results include 1 mW/ch, 200 e⁻ (rms) @ 1 MCPS

Future work

- Performance evaluation of SENSROC12.
- Application verification in personal dosimeter system.



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Thanks for your attentions.

Questions?